

# Reliability Test Services

We provide:

- Package-level and wafer-level reliability solutions, including a 300mm wafer level total qualification programme
- Real-time information of measurement of rate of degradation of materials used in production of devices during TQP



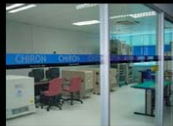
Test Structures Verification and Testing



Time-Dependent-Dielectric-Breakdown (TDDB)



Hot Carrier Injection (CH9010)



Chiron Semilab

## Test Structures Design



Grain Boundary diffusion



A pair of Box Cross Test Structures for the Measurement of CMP Dishing



Reliability Qualification - TDDB



-Rate of hot carrier trapping  
-Drain side

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